

§ 469.16

SUBPART A—SEMICONDUCTOR BAT EFFLUENT LIMITATIONS

Pollutant or pollutant property	Maximum for any 1 day	Average of daily values for 30 consecutive days
		Milligrams per liter (mg/l)
TTO ¹	1.37	(²)
Fluoride (T)	32.0	17.4

¹ Total toxic organics.
² Not applicable.

§ 469.16 Pretreatment standards for existing sources (PSES).

Except as provided in 40 CFR 403.7 and 403.13, any existing source subject to this subpart which introduces pollutants into a publicly owned treatment works must comply with 40 CFR part 403 and achieve the following pretreatment standards for existing sources (PSES):

(a)

SUBPART A—SEMICONDUCTOR PSES EFFLUENT LIMITATIONS

Pollutant or pollutant property	Maximum for any 1 day	Average of daily values for 30 consecutive days
		Milligrams per liter (mg/l)
TTO ¹	1.37	(²)

¹ Total toxic organics.
² Not applicable.

(b) An existing source submitting a certification in lieu of monitoring pursuant to §469.13 (c) and (d) of this regulation must implement the solvent management plan approved by the control authority.

§ 469.17 New source performance standards (NSPS).

Any new source subject to this subpart must achieve the following new source performance standards (NSPS).

40 CFR Ch. I (7–1–04 Edition)

SUBPART A—SEMICONDUCTOR NSPS EFFLUENT LIMITATIONS

Pollutant or pollutant property	Maximum for any 1 day	Average of daily values for 30 consecutive days
		Milligrams per liter (mg/l)
TTO ¹	1.37	(²)
Fluoride (T)	32.0	17.4
pH	(²)	(³)

¹ Total toxic organics.
² Not applicable.
³ Within the range of 6.0 to 9.0.

§ 469.18 Pretreatment standards for new sources (PSNS).

Except as provided in 40 CFR 403.7, any new source subject to this subpart which introduces pollutants into a publicly owned treatment works must comply with 40 CFR part 403 and achieve the following pretreatment standards for new sources (PSNS):

(a)

SUBPART A—SEMICONDUCTOR PSNS EFFLUENT LIMITATIONS

Pollutant or pollutant property	Maximum for any 1 day	Average of daily values for 30 consecutive days
		Milligrams per liter (mg/l)
TTO ¹	1.37	(²)

¹ Total toxic organics.
² Not applicable.

(b) A new source submitting a certification in lieu of monitoring pursuant to §469.13 (c) and (d) of this regulation must implement the solvent management plan approved by the control authority.

§ 469.19 Effluent limitations representing the degree of effluent reduction attainable by the application of the best conventional pollution control technology (BCT).

Except as provided in 40 CFR 125.30 through 125.32, any existing point source subject to this subpart must achieve the following effluent limitations representing the degree of effluent reduction attainable by the application of the best conventional pollution control technology (BCT):

Environmental Protection Agency

§ 469.24

SUBPART A—SEMICONDUCTOR BCT EFFLUENT LIMITATIONS

Pollutant or pollutant property	Maximum for any 1 day	Average of daily values for 30 consecutive days
pH	(¹)	(¹)

¹ Within the range 6.0 to 9.0.

Subpart B—Electronic Crystals Subcategory

§ 469.20 Applicability.

(a) The provisions of this subpart are applicable to discharges resulting from the manufacture of electronic crystals.

§ 469.21 Compliance dates.

The compliance date for the BAT fluoride limitation is as soon as possible as determined by the permit writer but in no event later than November 8, 1985. The compliance date for PSES for total toxic organics (TTO) is July 1, 1984 and for arsenic is November 8, 1985.

[48 FR 45250, Oct. 4, 1983, as amended at 49 FR 5923, Feb. 16, 1984]

§ 469.22 Specialized definitions.

The definitions in 40 CFR part 401 and the chemical analysis methods in 40 CFR part 136 apply to this subpart. In addition,

(a) The term “total toxic organics (TTO)” means the sum of the concentrations for each of the following toxic organic compounds which is found in the discharge at a concentration greater than ten (10) micrograms per liter:

- 1,2,4 Trichlorobenzene chloroform
- 1,2 Dichlorobenzene
- 1,3, Dichlorobenzene
- 1,4, Dichlorobenzene ethylbenzene
- 1,1,1 Trichloroethane methylene chloride naphthalene
- 2 Nitrophenol phenol bis (2-ethylhexyl) phthalate tetrachloroethylene toluene trichloroethylene
- 2 Chlorophenol
- 2,4 Dichlorophenol
- 4 Nitrophenol pentachlorophenol di-n-butyl phthalate anthracene
- 1,2 Diphenylhydrazine isophorone butyl benzyl phthalate
- 1,1 Dichloroethylene
- 2,4,6 Trichlorophenol carbon tetrachloride
- 1,2 Dichloroethane

1,1,2 Trichloroethane dichlorobromomethane

(b) The term “electronic crystals” means crystals or crystalline material which because of their unique structural and electronic properties are used in electronic devices. Examples of these crystals are crystals comprised of quartz, ceramic, silicon, gallium arsenide, and indium arsenide.

(c) The term “manufacture of electronic crystals” means the growing of crystals and/or the production of crystal wafers for use in the manufacture of electronic devices.

[48 FR 15394, Apr. 8, 1983, as amended at 48 FR 45250, Oct. 4, 1983]

§ 469.23 Monitoring.

The certification alternative to monitoring for Total Toxic Organics (TTO) described in § 469.13 (a), (b), (c), and (d) is applicable to this subpart.

(Approved by the Office of Management and Budget under control number 2040-0074)

[48 FR 15394, Apr. 8, 1983, as amended at 50 FR 4515, Jan. 31, 1985]

§ 469.24 Effluent limitations representing the degree of effluent reduction attainable by the application of the best practicable control technology currently available (BPT).

Except as provided in 40 CFR 125.30 through 32, any existing point source subject to this subpart must achieve the following effluent limitations representing the degree of effluent reduction attainable by the application of the best practicable control technology currently available (BPT):

SUBPART B—ELECTRONIC CRYSTALS BPT EFFLUENT LIMITATIONS

Pollutant or pollutant property	Maximum for any 1 day	Average of daily values for 30 consecutive days
TTO ¹	1.37	(³)
Arsenic (T) ²	2.09	0.83
Fluoride (T)	32.0	17.4
TSS	61.0	23.0
pH	(⁴)	(⁴)

¹ Total toxic organics.
² The arsenic (T) limitation only applies to manufacturers of gallium or indium arsenide crystals.
³ Not applicable.
⁴ Within the range of 6.0 to 9.0.